

Search Notes

Application/Control No.

09/652,862

Examiner

James D. Ewart

Applicant(s)/Patent under
Reexamination

CHANG ET AL.

Art Unit

2617

SEARCHED

Class	Subclass	Date	Examiner
455	12.1	4/24/2006	JDE
	13.1		
	427		
	429		
	456		
	458		
	562		
342	357.01		
	357.16		
	457		
244	158R		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
same as	above	4/24/2006	JDE

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR